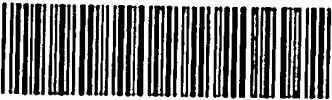


<b>Issue Classification</b>		Application/Control No.	Applicant(s)/Patent under Reexamination	
		10/791,135	CHEN ET AL.	
		Examiner	Art Unit	
		Jinhee J. Lee	2831	

ISSUE CLASSIFICATION			
ORIGINAL		CROSS REFERENCE(S)	
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)
174	99	174	100 72a
INTERNATIONAL CLASSIFICATION			
a	6	3	b 21/06
			1
			1
			1
			1
Jinhee Lee (Assistant Examiner) (Date)		Dean A. Reichard DEAN A. REICHARD SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800 (Primary Examiner) (Date)	
Donna Rivers 4/6/05 (Legal Instruments Examiner) (Date)		4/4/05	
Total Claims Allowed: 16			
		O.G. Print Claim(s)	O.G. Print Fig.
		1	3a, 3b, 4f

Claims renumbered in the same order as presented by applicant

Final	Original												
1		31		61		91		121		151		181	
2		32		62		92		122		152		182	
3		33		63		93		123		153		183	
4		34		64		94		124		154		184	
5		35		65		95		125		155		185	
6		36		66		96		126		156		186	
7		37		67		97		127		157		187	
8		38		68		98		128		158		188	
9		39		69		99		129		159		189	
10		40		70		100		130		160		190	
11		41		71		101		131		161		191	
12		42		72		102		132		162		192	
13		43		73		103		133		163		193	
14		44		74		104		134		164		194	
15		45		75		105		135		165		195	
16		46		76		106		136		166		196	
17		47		77		107		137		167		197	
18		48		78		108		138		168		198	
19		49		79		109		139		169		199	
20		50		80		110		140		170		200	
21		51		81		111		141		171		201	
22		52		82		112		142		172		202	
23		53		83		113		143		173		203	
24		54		84		114		144		174		204	
25		55		85		115		145		175		205	
26		56		86		116		146		176		206	
27		57		87		117		147		177		207	
28		58		88		118		148		178		208	
29		59		89		119		149		179		209	
30		60		90		120		150		180		210	

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